

PTO/SB/30 (5/2000)  
OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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**REQUEST  
FOR  
CONTINUED EXAMINATION (RCE)  
TRANSMITTAL**

Subsection (b) of 35 U.S.C. §132, effective on May 29, 2000,  
provides for continued examination of a utility or plant application  
filed on or after June 8, 1995.  
See The American Inventors Protection Act of 1999 (AIPA)

**Application Number: 10/756,366**

**Filing Date: January 14, 2004**

**First Named Inventor: Hiroaki NAKANO**

**Group Art Unit: 2811**

**Examiner Name: Thomas J. Magee**

**Attorney Docket Number: TAI 146**

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application.

**Note:** 37 C.F.R. § 1.114 is effective on May 29, 2000. If the above-identified application was filed prior to May 29, 2000, applicant may wish to consider filing a continued prosecution application (CPA) under 37 C.F.R. § 1.53 (d) (PTO/SB/29) instead of a RCE to be eligible for the patent term adjustment provisions of the AIPA. See changes to Application Examination and Provisional Application Practice, Interim Rule, 65 Fed. Reg. 14865 (Mar. 20, 2000), 1233 Off. Gaz. Pat. Office 47 (Apr. 11, 2000), which established RCE practice.

**1. Submission Required Under 37 C.F.R. § 1.114**

a. ☐ Previously Submitted

i. ☐ Consider the amendment(s) reply under 37 C.F.R. § 1.116 previously filed on \_\_\_\_\_  
(Any unentered amendment(s) referred to above will be entered).

ii. ☐ Consider the arguments in the Appeal Brief or Reply Brief previously filed on \_\_\_\_\_

iii. ☐ Other \_\_\_\_\_

b. ☒ Enclosed

i. ☒ Amendment/Reply

ii. ☐ Affidavit(s)/Declaration(s)

iii. ☐ Information Disclosure Statement (IDS)

iv. ☐ Other \_\_\_\_\_

07/06/2005 SDENBOB1 00000139 10756366

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790.00 DP

**2. Miscellaneous**

a. ☐ Suspension of action on the above-identified application is requested under 37 C.F.R. § 103(c) for a period of \_\_\_\_\_ months. (Period of suspension shall not exceed 3 months; Fee under 37 C.F.R. § 1.17 (i) required)

b. ☐ Other \_\_\_\_\_

**3. FEES** The RCE fee under 37 C.F.R. § 1.17(e) is required by 37 C.F.R. § 1.114 when the RCE is filed.

a. ☒ The Director is hereby authorized to charge the following fees, or credit any overpayments, to Deposit Account No. 18-0002

i. ☒ RCE fee required under 37 C.F.R. § 1.17(e) \$790

ii. ☐ Extension of time fee (37 C.F.R. §§ 1.136 and 1.17)

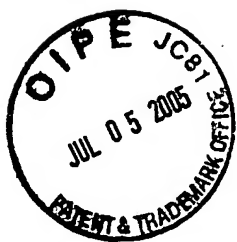
iii. ☐ Other \_\_\_\_\_

b. Check in the amount of ----- is enclosed

c. Payment by credit card (Form PTO-2038 enclosed) in the amount of \$790.00.

**SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT REQUIRED**

Name (Print or Type)	<b>RABIN &amp; BERDO, P.C. Nicholas S. Bromer</b>	23995	Registration Number <b>33,478</b>
Signature	<i>Nick Bromer</i>	Date	<b>July 5, 2005</b>



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2811  
Examiner: Thomas J. Magee  
Confirmation No.: 2358

In Re PATENT APPLICATION Of:

Applicant: Hiroaki Nakano )  
Serial No.: 10/756,366 )  
Filed: January 14, 2004 ) AMENDMENT  
For: CIRCUIT BOARD FOR MOUNTING ) in  
A SEMICONDUCTOR CHIP AND ) R.C.E.  
MANUFACTURING METHOD THEREOF )  
Attny Ref.: TAI 146 )

July 5, 2005

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

An RCE and an IDS are filed on even date with this paper, which is timely filed in response to the Final Official Action mailed on April 5, 2005.

No extension-of-time fee or IDS fee is due. However, please charge our Deposit Account No. 18-0002 if any fees are needed to enter this paper, and please advise us accordingly. It is noted that no petition is required because of the authorization to charge, but please consider this paper a petition for extension of time if needed.

Independent claims 1, 6, and 9 are amended. The amendments are supported in the original disclosure. The feature *an insulating substrate having a surface including mutually non-overlapping regions* is supported in Fig. 2, which clearly shows the three distinct and non-overlapping regions 28, 30, and 32 on the surface of the substrate 16, and in the original claims 1, 6, and 9.